

IMAGE DEFECT INSPECTION METHOD, IMAGE DEFECT INSPECTION
APPARATUS AND APPEARANCE INSPECTION APPARATUS

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ABSTRACT OF THE DISCLOSURE

10 A new image defect inspection method and a new image
defect inspection apparatus capable of being used for
automatic setting of a threshold value for an appearance
inspection apparatus with a high throughput have been
disclosed. According to the image defect inspection
15 method and the image defect inspection apparatus,
cumulative frequencies of gray level differences of the
corresponding parts of two images are calculated,
converted cumulative frequencies are calculated by
converting the cumulative frequencies so as to be linear
20 with the gray level differences in a predetermined
distribution, a straight line approximation to the
converted cumulative frequencies is calculated, and a
threshold value is determined from a predetermined
cumulative frequency based on the calculated straight
line approximation according to a predetermined
25 calculation method. Because there holds a linear
relationship between the converted cumulative frequencies
and the gray level differences, the following process for
determining a threshold value is facilitated.